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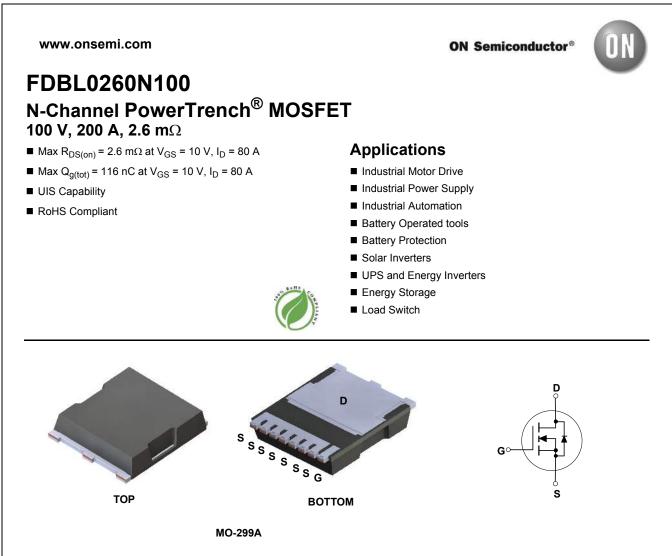


# **ON Semiconductor**®

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Please note: As part of the Fairchild Semiconductor integration, some of the Fairchild orderable part numbers will need to change in order to meet ON Semiconductor's system requirements. Since the ON Semiconductor product management systems do not have the ability to manage part nomenclature that utilizes an underscore (\_), the underscore (\_) in the Fairchild part numbers will be changed to a dash (-). This document may contain device numbers with an underscore (\_). Please check the ON Semiconductor website to verify the updated device numbers. The most current and up-to-date ordering information can be found at <a href="https://www.onsemi.com">www.onsemi.com</a>. Please email any questions regarding the system integration to <a href="https://www.onsemi.com">Fairchild\_questions@onsemi.com</a>.

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## **MOSFET Maximum Ratings** T<sub>C</sub> = 25 °C unless otherwise noted.

Symbol	Parameter			Ratings	Units	
V <sub>DS</sub>	Drain to Source Voltage			100	V	
V <sub>GS</sub>	Gate to Source Voltage			±20	V	
	Drain Current -Continuous	T <sub>C</sub> = 25°C	(Note 5)	200		
I <sub>D</sub>	-Continuous	T <sub>C</sub> = 100°C	(Note 5)	140	A	
	-Pulsed		(Note 4)	1000		
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	866	mJ	
D	Power Dissipation	T <sub>C</sub> = 25°C		250	w	
P <sub>D</sub>	Power Dissipation	T <sub>A</sub> = 25°C	(Note 1a)	3.5	vv	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature	Range		-55 to +175	°C	
Thermal Ch	naracteristics					
$R_{\theta JC}$	Thermal Resistance, Junction to Case		(Note 1)	0.6	°C/W	
R <sub>θJA</sub>	Thermal Resistance, Junction to Ambient		(Note 1a)	43		

### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDBL0260N100	FDBL0260N100	MO-299A	-	-	-

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Chara	acteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	100			V
$\Delta BV_{DSS}$ $\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, referenced to 25 °C		53		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V			1	μA
IGSS	Gate to Source Leakage Current	$V_{GS}$ = ±20 V, $V_{DS}$ = 0 V			±100	nA
On Chara	acteristics					
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250 μA	2	2.7	4	V
rDS(on)	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 80 \text{ A}$		2.1	2.6	mΩ
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 µA, referenced to 25 °C		-13		mV/°C
-	Forward Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 80 A		170		S
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10 V, 1 <sub>D</sub> = 00 A		170		3
Dynamic C <sub>iss</sub>	Characteristics			6175	9265	pF
Dynamic C <sub>iss</sub> C <sub>oss</sub>	Characteristics Input Capacitance Output Capacitance				9265 1995	
Dynamic C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Characteristics Input Capacitance	— V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V, — f = 1 MHz		6175 1330 40		pF
Dynamic C <sub>iss</sub> C <sub>oss</sub>	Characteristics Input Capacitance Output Capacitance			6175 1330	1995	pF pF
Dynamic C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> R <sub>g</sub>	Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance	— V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V, — f = 1 MHz		6175 1330 40	1995	pF pF pF
Dynamic C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> R <sub>g</sub> Switching	Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance	— V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V, — f = 1 MHz		6175 1330 40	1995	pF pF pF
Dynamic C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> R <sub>g</sub> Switching	Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance g Characteristics	— V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V, — f = 1 MHz		6175 1330 40 2.6	1995 60	pF pF pF Ω
Dynamic C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> R <sub>g</sub> Switching	Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance g Characteristics Turn-On Delay Time	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V, f = 1 MHz V <sub>GS</sub> = 0.5V, f = 1MHz		6175 1330 40 2.6 26	1995 60 42	pF pF pF Ω ns
Dynamic C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> Switching d(on)	Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance g Characteristics Turn-On Delay Time Rise Time	$V_{DS} = 50 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ f = 1 MHz $V_{GS} = 0.5 \text{ V}, \text{ f} = 1 \text{ MHz}$		6175 1330 40 2.6 26 34	1995 60 42 54	pF pF Ω ns
Dynamic Diss Doss Drss Rg Switching d(on) r d(off) f	Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance g Characteristics Turn-On Delay Time Rise Time Turn-Off Delay Time	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz $V_{GS} = 0.5 \text{ V}, \text{ f} = 1 \text{ MHz}$ $V_{DD} = 50 \text{ V}, \text{ I}_{D} = 80 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$ $V_{GS} = 0 \text{ to } 10 \text{ V}$		6175 1330 40 2.6 26 34 47	1995 60 42 54 75	pF pF pF Ω ns ns ns
Dynamic Ciss Coss Crss Rg Switching id(on) ir id(off) if Q <sub>q(TOT)</sub>	Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance g Characteristics Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz $V_{GS} = 0.5 \text{ V}, \text{ f} = 1 \text{ MHz}$ $V_{DD} = 50 \text{ V}, \text{ I}_{D} = 80 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$		6175 1330 40 2.6 26 34 47 19	1995 60 42 54 75 34	pF pF Ω ns ns ns ns
Dynamic C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub> R <sub>g</sub>	Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance Characteristics Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Total Gate Charge	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz $V_{GS} = 0.5 \text{ V}, \text{ f} = 1 \text{ MHz}$ $V_{DD} = 50 \text{ V}, \text{ I}_{D} = 80 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$ $V_{GS} = 0 \text{ to } 10 \text{ V}$		6175 1330 40 2.6 26 34 47 19 83	1995 60 42 54 75 34 116	pF pF Ω ns ns ns ns ns

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	-	200	А
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	-	1000	A
V <sub>SD</sub>	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 80 A	(Note 2)		0.8	1.3	V
		V <sub>GS</sub> = 0 V, I <sub>S</sub> = 40 A	(Note 2)		0.8	1.2	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 80 A, di/dt = 100 A/μs			71	113	ns
Q <sub>rr</sub>	Reverse Recovery Charge				121	194	nC

Notes:

 $R_{0LS}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{0LC}$  is guaranteed by design while  $R_{0CA}$  is determined by the user's board design.

a) 43 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.

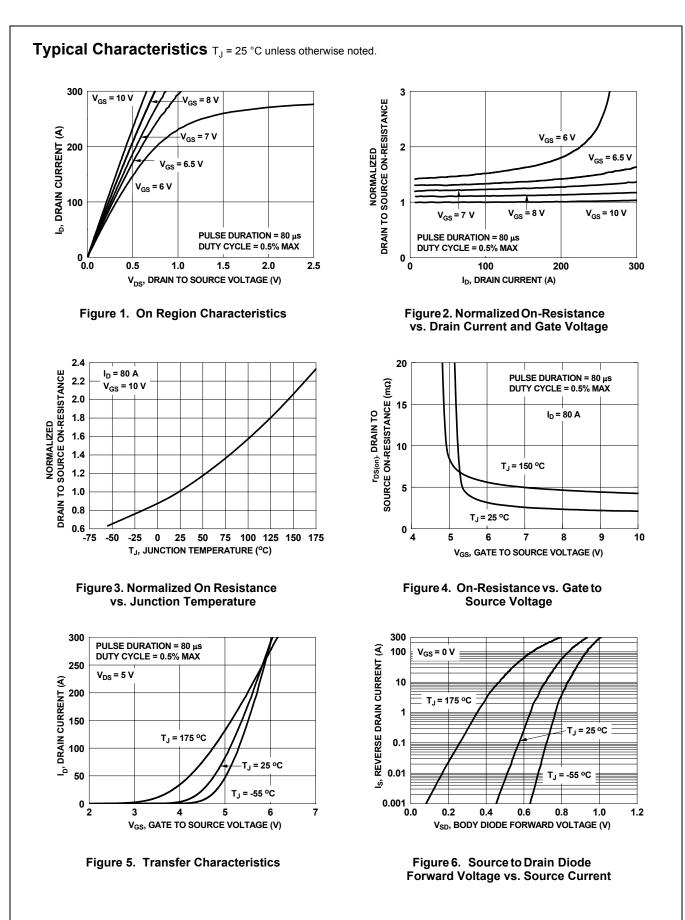
2. Pulse Test: Pulse Width < 300  $\mu s,$  Duty cycle < 2.0 %.

3.  $E_{AS}$  of 866 mJ is based on starting  $T_J$  = 25 °C, L = 0.3 mH,  $I_{AS}$  = 76 A,  $V_{DD}$  = 90 V,  $V_{GS}$  = 10 V. 100% test at L = 0.1 mH,  $I_{AS}$  = 110 A.

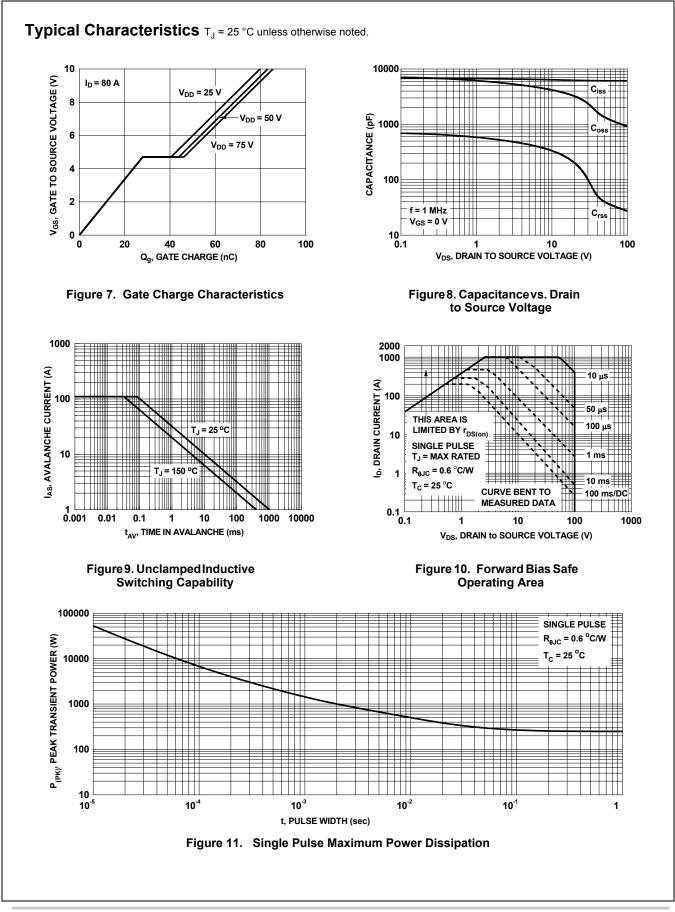
4. Pulsed Id please refer to Figure "Forward Bias Safe Operating Area" for more details.

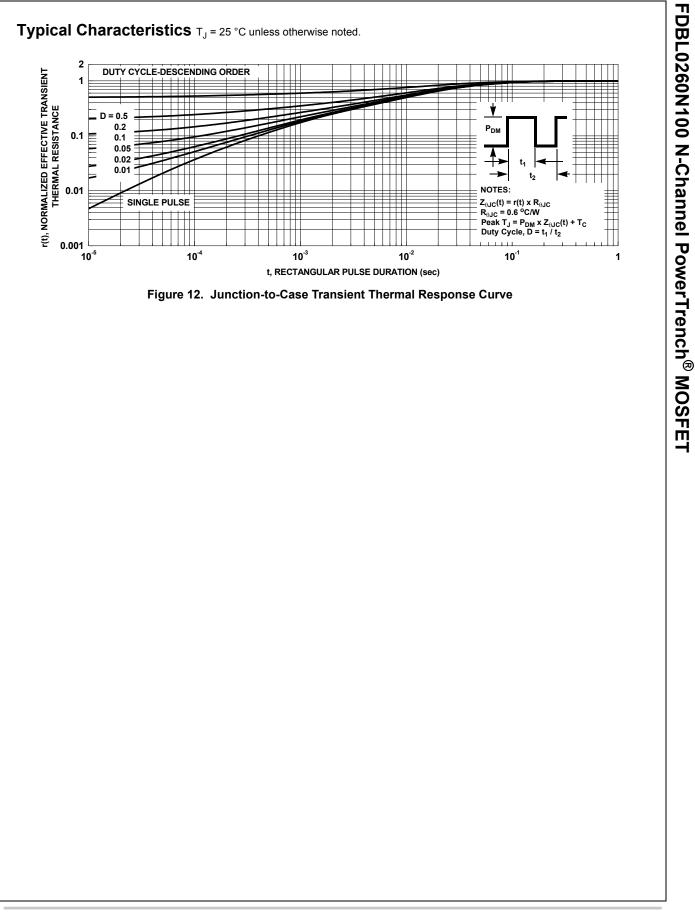
5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

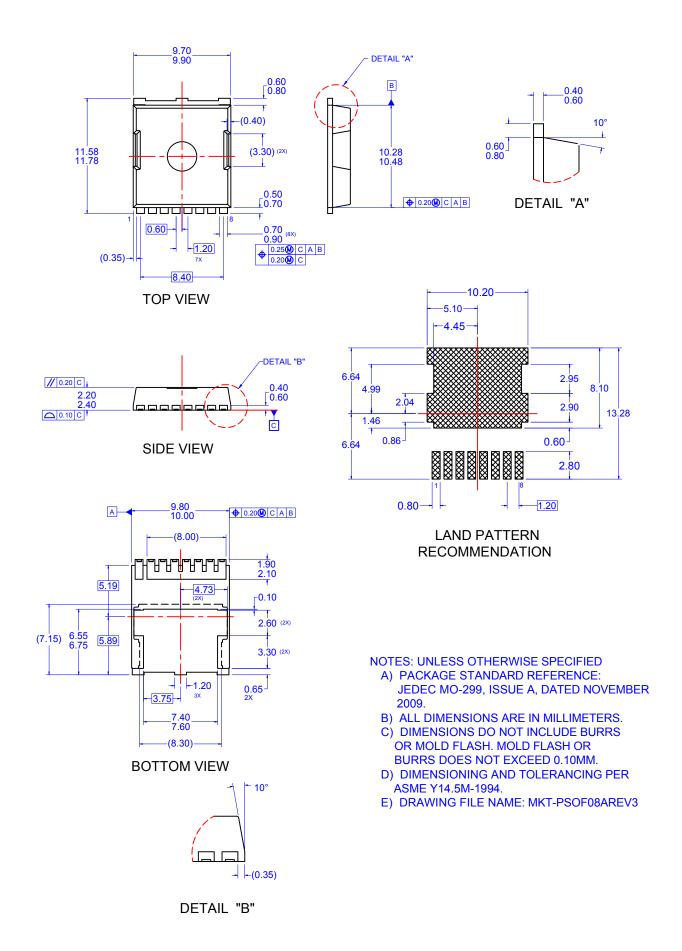
FDBL0260N100 N-Channel PowerTrench<sup>®</sup> MOSFET



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